

VN7004SLHTR Datasheet



<https://www.DiGi-Electronics.com>

| | |
|------------------------------|--|
| DiGi Electronics Part Number | VN7004SLHTR-DG |
| Manufacturer | STMicroelectronics |
| Manufacturer Product Number | VN7004SLHTR |
| Description | HIGH-SIDE DRIVER WITH CURRENTSEN |
| Detailed Description | Power Switch/Driver 1:1 N-Channel 135A OctaPAK 7+1 |



Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com

DiGi is a global authorized distributor of electronic components.

Purchase and inquiry

Manufacturer Product Number:

VN7004SLHTR

Series:

-

Switch Type:

General Purpose

Ratio - Input:Output:

1:1

Output Type:

N-Channel

Voltage - Load:

-

Current - Output (Max):

135A

Input Type:

Non-Inverting

Operating Temperature:

-40°C ~ 150°C (Tj)

Supplier Device Package:

OctaPAK 7+1

Base Product Number:

VN7007

Manufacturer:

STMicroelectronics

Product Status:

Active

Number of Outputs:

1

Output Configuration:

High Side

Interface:

Logic

Voltage - Supply (Vcc/Vdd):

4V ~ 28V

Rds On (Typ):

4mOhm

Features:

Load Discharge, Status Flag

Mounting Type:

Surface Mount

Package / Case:

OctaPAK (7 leads + Tab)

Environmental & Export classification

RoHS Status:

ROHS3 Compliant

REACH Status:

REACH Unaffected

HTSUS:

8542.39.0001

Moisture Sensitivity Level (MSL):

3 (168 Hours)

ECCN:


EAR99

High-side driver with CurrentSense analog feedback for automotive seat heating systems



Features

| | | |
|-----------------------------------|------------|--------------|
| Max transient supply voltage | V_{CC} | 40 V |
| Operating voltage range | V_{CC} | 4 to 28 V |
| Typ. on-state resistance (per Ch) | R_{ON} | 4 m Ω |
| Current limitation (typ.) | I_{LIMH} | 135 A |
| Stand-by current (max.) | I_{STBY} | 0.5 μ A |

- AEC-Q100 qualified 
- General
 - Single channel smart high-side driver with CurrentSense analog feedback
 - Very low standby current
 - Compatible with 3.0 V and 5 V CMOS outputs
- Diagnostic functions
 - Overload and short to ground (power limitation) indication
 - Thermal shutdown indication
 - OFF-state open-load detection
 - Output short to V_{CC} detection
- Protections
 - Undervoltage shutdown
 - Overvoltage clamp
 - Load current limitation
 - Self limiting of fast thermal transients
 - Loss of ground and loss of V_{CC}
 - Configurable latch-off on overtemperature or power limitation
 - Reverse battery
 - Electrostatic discharge protection

Product status link

[VN7004SLH](#)

Product summary

| | |
|-------------------|---------------|
| Order code | VN7004SLHTR |
| Package | Octopack |
| Packing | Tape and reel |

Application

Specially intended for Automotive seat heating systems.

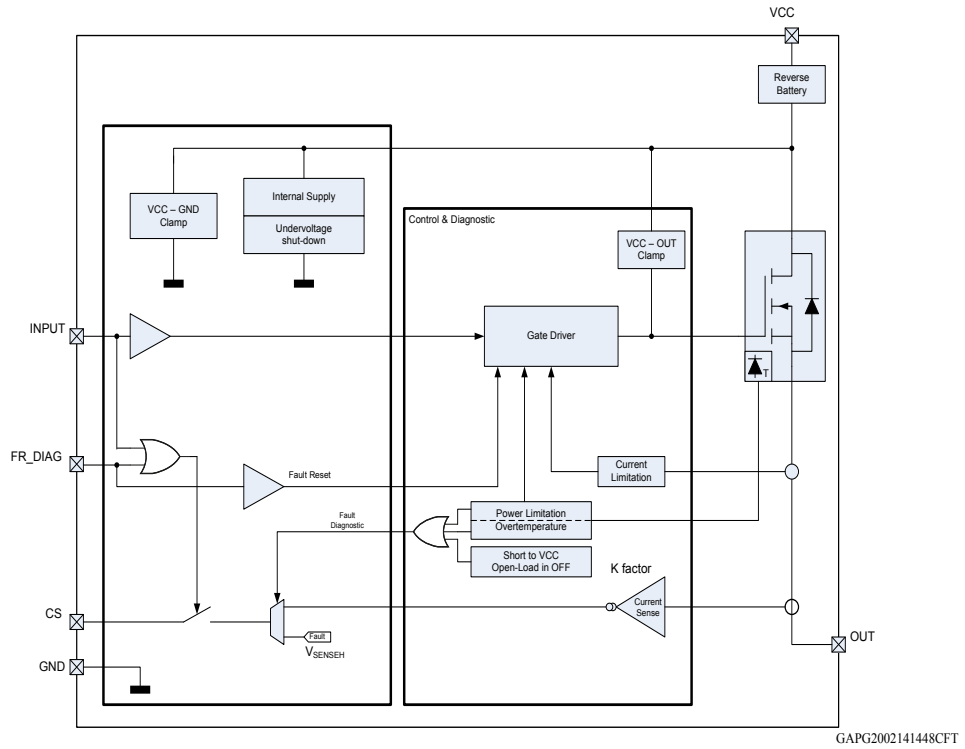
Description

The device is a single channel high-side driver manufactured using ST proprietary VIPower technology and housed in the Octopack package. The device is designed to drive 12 V automotive grounded loads through a 3 V and 5 V CMOS-compatible interface, and to provide protection and diagnostics.

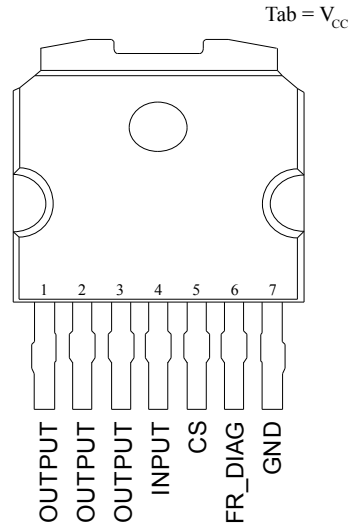
The device integrates advanced protective functions such as load current limitation, overload active management by power limitation and overtemperature shutdown.

A combination of INPUT and FR_DIAG pins latches the output in case of fault, disables the latch-off functionality and enables OFF-state diagnostic.

1 Block diagram and pin description

Figure 1. Block diagram

Table 1. Pin functions

| Name | Function |
|-----------------|--|
| V _{CC} | Battery connection. |
| OUTPUT | Power outputs. All the pins must be connected together. |
| GND | Ground connection. |
| INPUT | Voltage controlled input pin with hysteresis. Compatible with 3 V and 5 V CMOS outputs. It controls output switch state. |
| CS | Analog current sense output pin delivers a current proportional to the load current. |
| FR_DIAG | It sets auto-restart and latch-off protection. Moreover, it enables OFF-state diagnostic. |

Figure 2. Configuration diagram (top view)


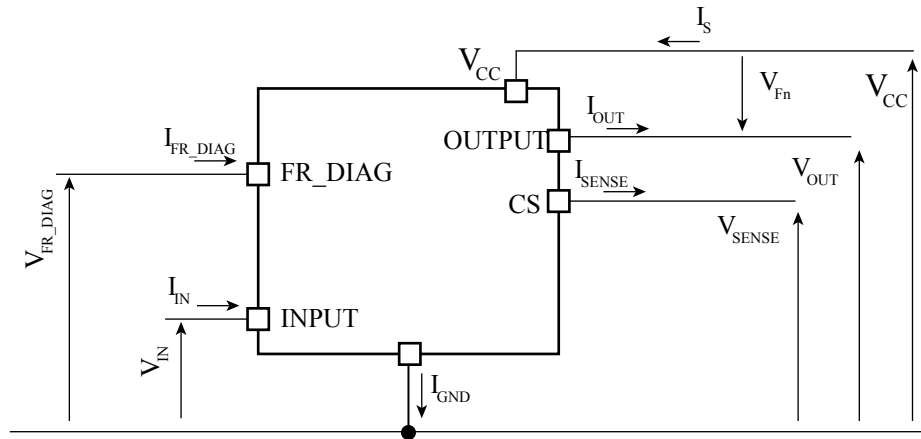
GAPG2804161118CFT

Table 2. Suggested connections for unused and not connected pins

| Connection / pin | CS | N.C. | Output | Input | FR_DIAG |
|------------------|-----------------------|------------------|-------------|------------------------|------------------------|
| Floating | Not allowed | X ⁽¹⁾ | X | X | X |
| To ground | Through 1 kΩ resistor | X | Not allowed | Through 15 kΩ resistor | Through 15 kΩ resistor |

1. X: do not care.

2 Electrical specification

Figure 3. Current and voltage conventions


GAPG0310141204CFT

Note: $V_F = V_{OUT} - V_{CC}$ when $V_{OUT} > V_{CC}$ and $INPUT = LOW$

2.1 Absolute maximum ratings

Stressing the device above the rating listed in Table 3. Absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to the conditions in the table below for extended periods may affect device reliability.

Table 3. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|--|--------------------|------|
| V_{CC} | DC supply voltage | 38 | V |
| $-V_{CC}$ | Reverse DC supply voltage | 16 | |
| V_{CCPK} | Maximum transient supply voltage (ISO7637-2:2004 Pulse 5b level IV clamped to 40 V; $R_L = 4 \Omega$) | 40 | |
| $-I_{GND}$ | DC reverse ground pin current | 200 | mA |
| I_{OUT} | OUTPUT DC output current | Internally limited | A |
| $-I_{OUT}$ | Reverse DC output current | 38 | |
| I_{IN} | INPUT DC input current | -1 to 10 | mA |
| I_{FR_DIAG} | FR_DIAG DC input current | | |
| I_{SENSE} | CS pin DC output current ($V_{GND} = V_{CC}$ and $V_{SENSE} < 0 V$) | 10 | mA |
| | CS pin DC output current in reverse ($V_{CC} < 0 V$) | -20 | |
| E_{MAX} | Maximum switching energy (single pulse) ($T_{DEMAG} = 0.13 ms$; $T_{jstart} = 150 \text{ }^\circ\text{C}$) | 105 | mJ |



| Symbol | Parameter | Value | Unit |
|------------------|--|------------|------|
| V _{ESD} | Electrostatic discharge (JEDEC 22A-114F) | 4000 | V |
| | • INPUT | 2000 | V |
| | • CurrentSense | 4000 | V |
| | • FR_DIAG | 4000 | V |
| | • OUTPUT | 4000 | V |
| | • V _{CC} | 4000 | V |
| V _{ESD} | Charge device model (CDM-AEC-Q100-011) | 750 | V |
| T _j | Junction operating temperature | -40 to 150 | °C |
| T _{stg} | Storage temperature | -55 to 150 | |

2.2 Thermal data

Table 4. Thermal data

| Symbol | Parameter | Typ. value | Unit |
|-----------------------|--|------------|------|
| R _{thj-case} | Thermal resistance junction-case ⁽¹⁾ | 1.45 | °C/W |
| R _{thj-amb} | Thermal resistance junction-ambient (JEDEC JESD 51-5) ⁽²⁾ | 58.1 | |
| R _{thj-amb} | Thermal resistance junction-ambient (JEDEC JESD 51-7) ⁽¹⁾ | 15.6 | |

1. Device mounted on four-layers 2s2p PCB

2. Device mounted on two-layers 2s0p PCB with 2 cm² heatsink copper trace

2.3 Main electrical characteristics

7 V < V_{CC} < 28 V; -40°C < T_j < 150°C, unless otherwise specified.

All typical values refer to V_{CC} = 13 V; T_j = 25°C, unless otherwise specified.

Table 5. Power section

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------|--|---|------|------|------|------|
| V _{CC} | Operating supply voltage | | 4 | 13 | 28 | V |
| V _{USD} | Undervoltage shutdown | | | | 4 | |
| V _{USDReset} | Undervoltage shutdown reset | | | | 5 | |
| V _{USDhyst} | Undervoltage shutdown hysteresis | | | 0.3 | | |
| R _{ON} | On-state resistance | I _{OUT} = 15 A; T _j = 25°C | | 4 | | mΩ |
| | | I _{OUT} = 15 A; T _j = 150°C | | | 8 | |
| | | I _{OUT} = 15 A; V _{CC} = 4 V; T _j = 25°C | | | 6 | |
| R _{ON_Rev} | R _{DS(on)} in reverse battery condition | V _{CC} = -13 V; I _{OUT} = -15 A; T _j = 25°C | | 4 | | mΩ |
| V _{clamp} | Clamp voltage | I _S = 20 mA; T _j = -40°C | 38 | | | V |
| | | I _S = 20 mA; 25°C < T _j < 150°C | 41 | 46 | 52 | V |
| I _{STBY} | Supply current in standby at V _{CC} = 13 V ⁽¹⁾ | V _{CC} = 13 V; V _{IN} = V _{OUT} = V _{FR_DIAG} = 0 V; T _j = 25°C | | | 0.5 | μA |
| | | V _{CC} = 13 V; V _{IN} = V _{OUT} = V _{FR_DIAG} = 0 V; T _j = 85°C ⁽²⁾ | | | 1.4 | |



| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|---|---|------|------|------|---------------|
| I_{STBY} | Supply current in standby at $V_{CC} = 13\text{ V}$ ⁽¹⁾ | $V_{CC} = 13\text{ V}$; $V_{IN} = V_{OUT} = V_{FR_DIAG} = 0\text{ V}$; $T_j = 125^\circ\text{C}$ | | | 11 | μA |
| t_{D_STBY} | Standby mode blanking time | $V_{CC} = 13\text{ V}$; $V_{IN} = 5\text{ V}$; $V_{FR_DIAG} = 0\text{ V}$; $I_{OUT} = 0\text{ A}$ | 200 | 1150 | 2000 | μs |
| $I_{S(ON)}$ | Supply current | $V_{CC} = 13\text{ V}$; $V_{FR_DIAG} = 0\text{ V}$; $V_{IN} = 5\text{ V}$; $I_{OUT} = 0\text{ A}$ | | 4 | 6.5 | mA |
| $I_{GND(ON)}$ | Control stage current consumption in ON state. All channels active. | $V_{CC} = 13\text{ V}$; $V_{FR_DIAG} = 5\text{ V}$; $V_{IN} = 5\text{ V}$; $I_{OUT} = 15\text{ A}$ | | | 9 | mA |
| $I_{L(off)}$ | Off-state output current at $V_{CC} = 13\text{ V}$ | $V_{IN} = V_{OUT} = 0\text{ V}$; $V_{CC} = 13\text{ V}$; $T_j = 25^\circ\text{C}$ | 0 | 0.01 | 0.5 | μA |
| | | $V_{IN} = V_{OUT} = 0\text{ V}$; $V_{CC} = 13\text{ V}$; $T_j = 125^\circ\text{C}$ | 0 | | 11 | |
| V_F | Output - V_{CC} diode voltage | $I_{OUT} = -15\text{ A}$; $T_j = 150^\circ\text{C}$ | | | 0.7 | V |

1. PowerMOS leakage included.
2. Parameter specified by design; not subject to production test.

Table 6. Switching

| $V_{CC} = 13\text{ V}$; $-40^\circ\text{C} < T_j < 150^\circ\text{C}$, unless otherwise specified | | | | | | |
|---|--|---------------------|-------|-------|-------------------|------------------------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| $t_{d(on)}$ ⁽¹⁾ | Turn-on delay time | $R_L = 1.8\ \Omega$ | 290 | 640 | 1100 | μs |
| $t_{d(off)}$ ⁽¹⁾ | Turn-off delay time | | 160 | 330 | 510 | |
| $(dV_{OUT}/dt)_{on}$ ⁽¹⁾ | Turn-on voltage slope | $R_L = 1.8\ \Omega$ | 0.015 | 0.023 | 0.041 | $\text{V}/\mu\text{s}$ |
| $(dV_{OUT}/dt)_{off}$ ⁽¹⁾ | Turn-off voltage slope | | 0.018 | 0.031 | 0.056 | |
| W_{ON} | Switching energy losses at turn-on (t_{won}) | $R_L = 1.8\ \Omega$ | — | 11.5 | 18 ⁽²⁾ | mJ |
| W_{OFF} | Switching energy losses at turn-off (t_{woff}) | $R_L = 1.8\ \Omega$ | — | 8 | 12 ⁽²⁾ | mJ |
| t_{SKEW} ⁽¹⁾ | Differential Pulse skew ($t_{PHL} - t_{PLH}$) | $R_L = 1.8\ \Omega$ | -780 | -410 | -40 | μs |

1. See Figure 6. Switching times and Pulse skew.
2. Parameter guaranteed by design and characterization; not subject to production test.

Table 7. Logic inputs

| $7\text{ V} < V_{CC} < 28\text{ V}$; $-40^\circ\text{C} < T_j < 150^\circ\text{C}$ | | | | | | |
|---|--------------------------|-------------------------|------|------|------|---------------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| INPUT characteristics | | | | | | |
| V_{IL} | Input low level voltage | | | | 0.9 | V |
| I_{IL} | Low level input current | $V_{IN} = 0.9\text{ V}$ | 1 | | | μA |
| V_{IH} | Input high level voltage | | 2.1 | | | V |
| I_{IH} | High level input current | $V_{IN} = 2.1\text{ V}$ | | | 10 | μA |
| $V_{I(hyst)}$ | Input hysteresis voltage | | 0.2 | | | V |
| V_{ICL} | Input clamp voltage | $I_{IN} = 1\text{ mA}$ | 5.3 | | 7.5 | V |
| | | $I_{IN} = -1\text{ mA}$ | | -0.7 | | |
| FR_DIAG characteristics ($7\text{ V} < V_{CC} < 18\text{ V}$) | | | | | | |
| V_{FR_DIAGL} | Input low level voltage | | | | 0.9 | V |



| 7 V < V _{CC} < 28 V; -40°C < T _j < 150°C | | | | | | |
|--|--------------------------|-------------------------|------|------|------|------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| I _{FR_DIAGL} | Low level input current | V _{IN} = 0.9 V | 1 | | | μA |
| V _{FR_DIAGH} | Input high level voltage | | 2.1 | | | V |
| I _{FR_DIAGH} | High level input current | V _{IN} = 2.1 V | | | 10 | μA |
| V _{FR_DIAG(hyst)} | Input hysteresis voltage | | 0.2 | | | V |
| V _{FR_DIAGCL} | Input clamp voltage | I _{IN} = 1 mA | 5.3 | | 7.5 | V |
| | | I _{IN} = -1 mA | | -0.7 | | |

Table 8. Protections

| 7 V < V _{CC} < 18 V; -40°C < T _j < 150°C | | | | | | |
|--|---|---|----------------------|----------------------|----------------------|------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| I _{LIMH} ⁽¹⁾ | DC short circuit current | V _{CC} = 13 V | 80 | 135 | 175 | A |
| | | 4 V < V _{CC} < 18 V ⁽²⁾ | | | 175 | |
| I _{LIML} | Short circuit current during thermal cycling | V _{CC} = 13 V; T _R < T _j < T _{TSD} | | 38 | | A |
| T _{TSD} | Shutdown temperature | | 150 | 175 | 200 | °C |
| T _R | Reset temperature ⁽²⁾ | | T _{RS} + 1 | T _{RS} + 7 | | °C |
| T _{RS} | Thermal reset of fault diagnostic indication | V _{FR_DIAG} = 5 V; | 135 | | | °C |
| T _{HYST} | Thermal hysteresis (T _{TSD} - T _R) ⁽²⁾ | | | 7 | | °C |
| ΔT _{J_SD} | Dynamic temperature | V _{CC} = 13 V | | 60 | | K |
| t _{LATCH_RST} | Fault reset time for output unlatch ⁽²⁾ | V _{FR_DIAG} = 5 V to 0 V; V _{IN} = 5 V | 3 | 10 | 20 | μs |
| V _{DEMAG} | Turn-off output voltage clamp | I _{OUT} = 2 A; L = 6 mH; T _j = -40°C | V _{CC} - 38 | | | V |
| | | I _{OUT} = 2 A; L = 6 mH; T _j = 25°C to 150°C | V _{CC} - 41 | V _{CC} - 46 | V _{CC} - 52 | |

1. Parameter guaranteed by an indirect test sequence.

2. Parameter guaranteed by design and characterization; not subject to production test.

Table 9. CurrentSense

| 7 V < V _{CC} < 18 V; -40°C < T _j < 150°C | | | | | | |
|--|--------------------------------------|---|------|-------|-------|------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| V _{SENSE_CL} | CurrentSense clamp voltage | V _{FR_DIAG} = 0 V; I _{SENSE} = 1 mA | -17 | | -12 | V |
| | | V _{FR_DIAG} = 0 V; I _{SENSE} = -1 mA | | 7 | | V |
| CurrentSense characteristics | | | | | | |
| K ₀ | I _{OUT} /I _{SENSE} | I _{OUT} = 1 A; V _{SENSE} = 0.5 V | 9000 | 16650 | 24500 | |
| dK ₀ /K ₀ ^{(1) (2)} | Current sense ratio drift | I _{OUT} = 1 A; V _{SENSE} = 0.5 V | -30 | | 30 | % |



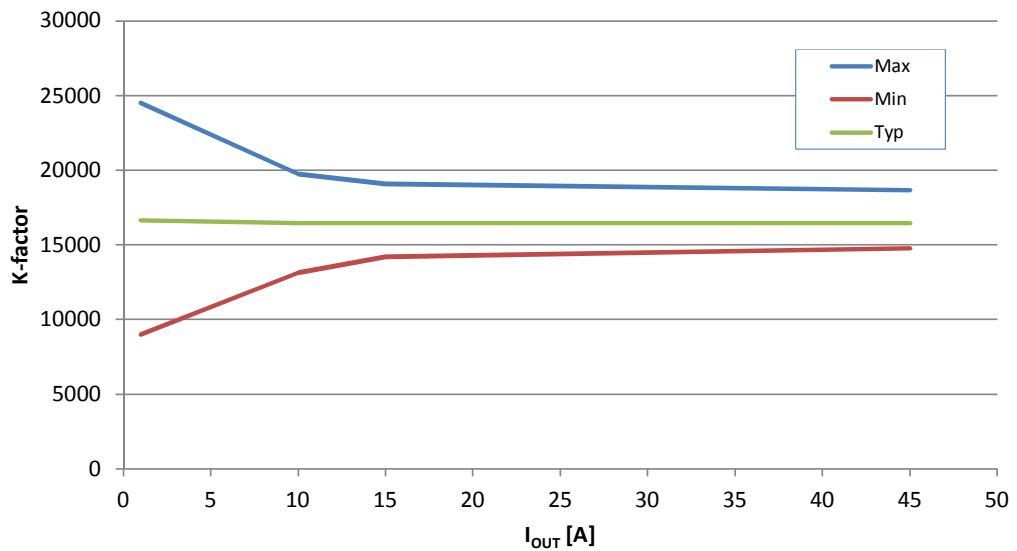
| 7 V < V _{CC} < 18 V; -40°C < T _j < 150°C | | | | | | |
|--|---|---|-------|-------|-------|------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| K ₁ | I _{OUT} /I _{SENSE} | I _{OUT} = 7 A; V _{SENSE} = 4 V | 13150 | 16450 | 19750 | |
| dK ₁ /K ₁ ^{(1) (2)} | Current sense ratio drift | I _{OUT} = 7 A; V _{SENSE} = 4 V | -10 | | 10 | % |
| K ₂ | I _{OUT} /I _{SENSE} | I _{OUT} = 12 A; V _{SENSE} = 4 V | 14200 | 16450 | 19100 | |
| dK ₂ /K ₂ ^{(1) (2)} | Current sense ratio drift | I _{OUT} = 12 A; V _{SENSE} = 4 V | -7 | | 7 | % |
| K ₃ | I _{OUT} /I _{SENSE} | I _{OUT} = 45 A; V _{SENSE} = 4 V | 14760 | 16450 | 18670 | |
| dK ₃ /K ₃ ^{(1) (2)} | Current sense ratio drift | I _{OUT} = 45 A; V _{SENSE} = 4 V | -5 | | 5 | % |
| I _{SENSE0} | CurrentSense leakage current | CurrentSense disabled: V _{FR_DIAG} = 0 V | 0 | | 0.5 | μA |
| | | CurrentSense disabled: -1 V < V _{SENSE} < 5 ⁽¹⁾ | -0.5 | | 0.5 | μA |
| | | CurrentSense enabled: V _{IN} = 5 V; I _{OUT} = 0 A | 0 | | 25 | μA |
| V _{OUT_CSD} ⁽¹⁾ | Output Voltage for CurrentSense shutdown | V _{FR_DIAG} = 5 V; R _{SENSE} = 2.7 kΩ; V _{IN} = 5 V; I _{OUT} = 15 A | | 5 | | V |
| V _{SENSE_SAT} | Multisense saturation voltage | V _{CC} = 7 V; R _{SENSE} = 10 kΩ; V _{FR_DIAG} = 5 V; V _{IN} = 5 V; I _{OUT} = 15 A; T _j = -40°C | 5 | | | V |
| I _{SENSE_SAT} ⁽¹⁾ | CS saturation current | V _{CC} = 7 V; V _{SENSE} = 4 V; V _{IN} = 5 V; V _{FR_DIAG} = 5 V; T _j = 150°C | 4 | | | mA |
| I _{OUT_SAT} ⁽¹⁾ | Output saturation current | V _{CC} = 7 V; V _{SENSE} = 4 V; V _{IN} = 5 V; V _{FR_DIAG} = 5 V; T _j = -150°C | 75 | | | A |
| OFF-state diagnostic | | | | | | |
| V _{OL} | OFF-state open-load voltage detection threshold | V _{IN} = 0 V; V _{FR_DIAG} = 5 V | 2 | 3 | 4 | V |
| I _{L(off2)} | OFF-state output sink current | V _{IN} = 0 V; V _{OUT} = V _{OL} ; T _j = -40°C to 125°C | -100 | | -15 | μA |
| t _{DSTKON} | OFF-state diagnostic delay time from falling edge of INPUT (see Figure 7. T _{DSTKON}) | V _{IN} = 5 V to 0 V; V _{FR_DIAG} = 5 V; I _{OUT} = 0 A; V _{OUT} = 4 V | 400 | 1480 | 2500 | μs |
| t _{D_OL_V} | Settling time for valid OFF-state open load diagnostic indication from rising edge of FR_DIAG | V _{IN} = 0 V; V _{FR} = 0 V; V _{OUT} = 4 V; V _{FR_DIAG} = 0 V to 5 V | | | 60 | μs |
| t _{D_VOL} | OFF-state diagnostic delay time from rising edge of V _{OUT} | V _{IN} = 0 V; V _{FR_DIAG} = 5 V; V _{OUT} = 0 V to 4 V | | 5 | 30 | μs |
| Fault diagnostic feedback (see Table 10. Truth table) | | | | | | |
| V _{SENSEH} | CurrentSense output voltage in fault condition | V _{CC} = 13 V; V _{IN} = 0 V; V _{FR_DIAG} = 5 V; I _{OUT} = 0 A; V _{OUT} = 4 V; R _{SENSE} = 1 kΩ | 5 | | 6.6 | V |
| I _{SENSEH} | CurrentSense output current in fault condition | V _{CC} = 13 V; V _{SENSE} = 5 V | 7 | 20 | 30 | mA |
| CurrentSense timings (current sense mode) ⁽³⁾ | | | | | | |
| t _{DSENSE2H} | Current sense settling time from rising edge of INPUT | V _{IN} = 0 V to 5 V; V _{FR_DIAG} = 5 V; R _{SENSE} = 1 kΩ; R _L = 0.87 Ω | | 1200 | 3750 | μs |



| 7 V < V _{CC} < 18 V; -40°C < T _j < 150°C | | | | | | |
|--|---|---|------|------|------|------|
| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| $\Delta t_{\text{DSENSE2H}}$ | Current sense settling time from rising edge of I _{OUT} (dynamic response to a step change of I _{OUT}) | V _{IN} = 5 V; V _{FR_DIAG} = 5 V; R _{SENSE} = 1 kΩ; I _{SENSE} = 90 % of I _{SENSEMAX} ; R _L = 0.87 Ω | | | 690 | μs |
| t_{DSENSE2L} | Current sense turn-off delay time from falling edge of INPUT | V _{IN} = 5 V to 0 V; V _{FR_DIAG} = 5 V; R _{SENSE} = 1 kΩ; R _L = 0.87 Ω | | 510 | 880 | μs |

1. Parameter guaranteed by design and characterization; not subject to production test.
2. All values refer to V_{CC} = 13 V; T_j = 25°C, unless otherwise specified.
3. Transition delay is measured up to ±10% of final conditions.

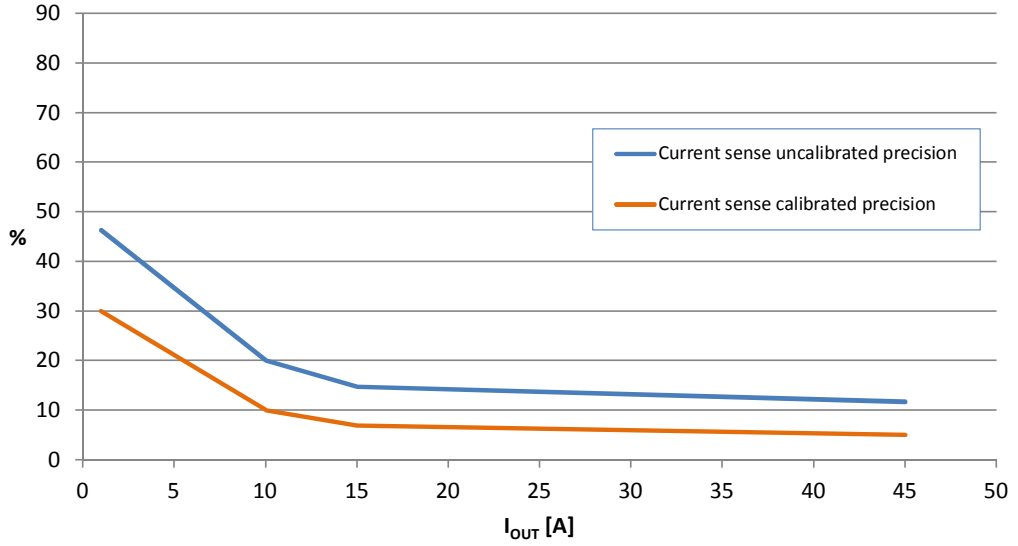
Figure 4. I_{OUT}/I_{SENSE} versus I_{OUT}



GADG1207161458SMD



Figure 5. Current sense precision vs. I_{OUT}



GADG1207161502SMD

Figure 6. Switching times and Pulse skew

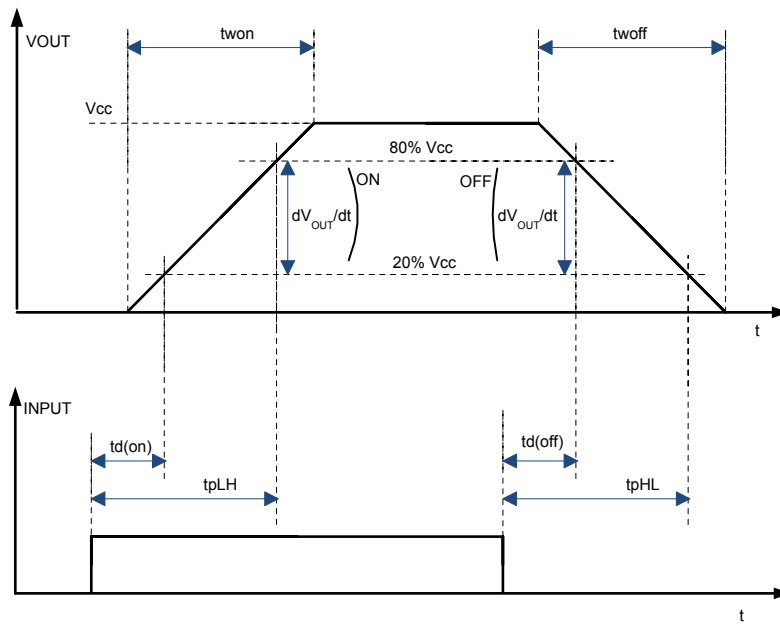
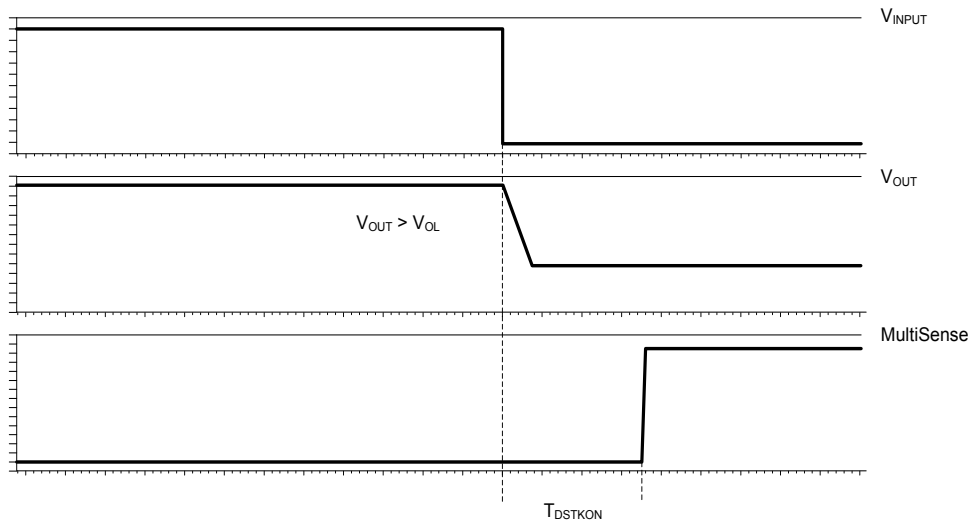




Figure 7. T_{DSTKON}



GAPG2609141140CFT

Table 10. Truth table

| Mode | Conditions | IN | FR_DIAG | OUT | Current Sense | Comments |
|-------------------------|--|----|---------|-------|---|--|
| Stand by | All logic inputs low | L | L | L | Hi-Z | Low quiescent current consumption |
| Normal | Nominal load connected; $T_j < 150^\circ\text{C}$ | L | H | L | 0 | OFF-state diagnostic enabled |
| | | H | L | H | $I_{\text{SENSE}} = 1/K * I_{\text{OUT}}$ | Autorestart mode |
| | | H | H | H | $I_{\text{SENSE}} = 1/K * I_{\text{OUT}}$ | Latch-off mode |
| Overload | Overload or short to GND causing: $T_j > T_{\text{TSD}}$ or $\Delta T_j > \Delta T_{j_SD}$ | H | L | H | V_{SENSEH} | Autorestart mode |
| | | H | H | H | V_{SENSEH} | Latch-off mode |
| Under-voltage | $V_{\text{CC}} < V_{\text{USD}}$ (falling) | X | X | L | Hi-Z | Re-start when $V_{\text{CC}} > V_{\text{USD}} + V_{\text{USDhyst}}$ (rising) |
| OFF-state diagnostics | Short to V_{CC} | L | H | H | V_{SENSEH} | |
| | Open-load | L | H | H | | External pull-up |
| Negative output voltage | Inductive loads turn-off | L | X | < 0 V | 0 | |

Table 11. FR_DIAG functionality

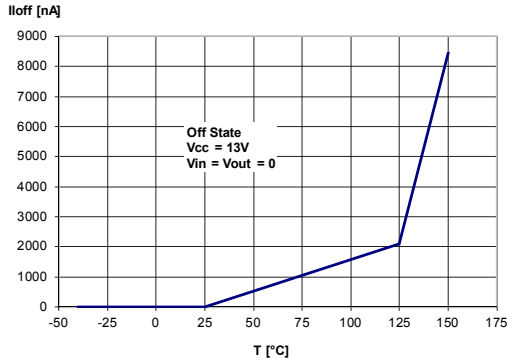
| FR_DIAG | Input | Diagnostic | Overload protection |
|---------|-------|--------------------------------|---------------------|
| 0 | 0 | Disabled | X ⁽¹⁾ |
| 0 | 1 | Enabled | Auto-restart |
| 1 | 0 | Enabled (OFF-state diagnostic) | X ⁽¹⁾ |
| 1 | 1 | Enabled | Latch-off |

1. X: do not care.



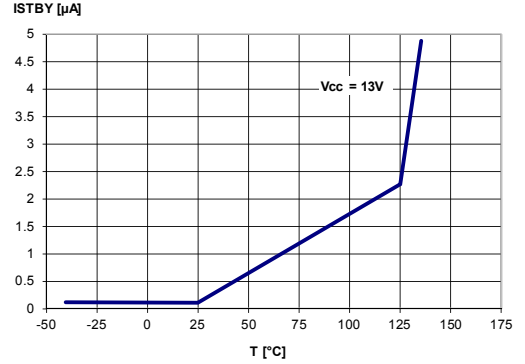
2.4 Electrical characteristics curves

Figure 8. OFF-state output current



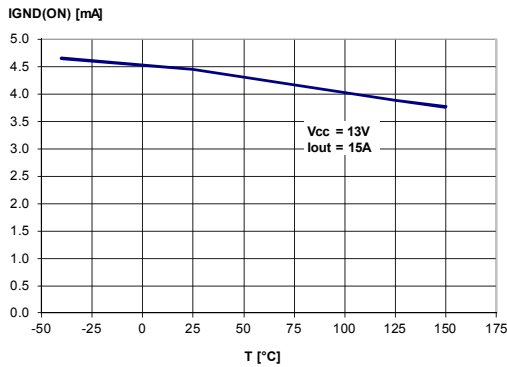
GADG1207161530SMD

Figure 9. Standby current



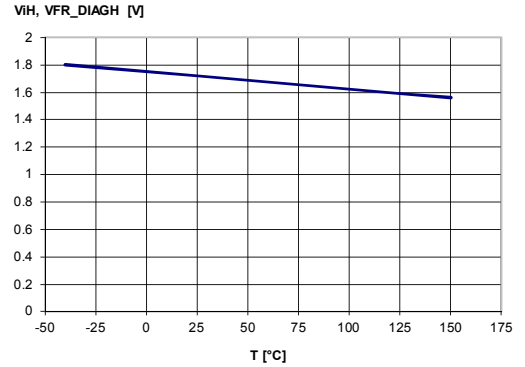
GADG1207161531SMD

Figure 10. $I_{GND(ON)}$ vs. I_{out}



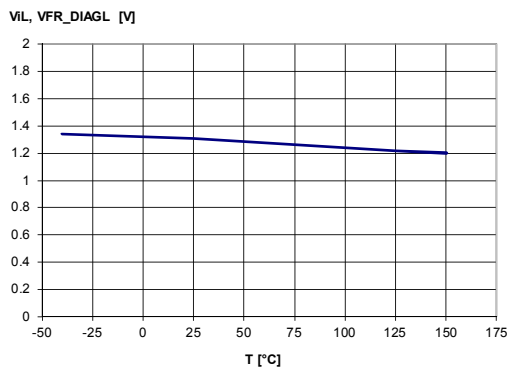
GADG1207161532SMD

Figure 11. Logic input high level voltage



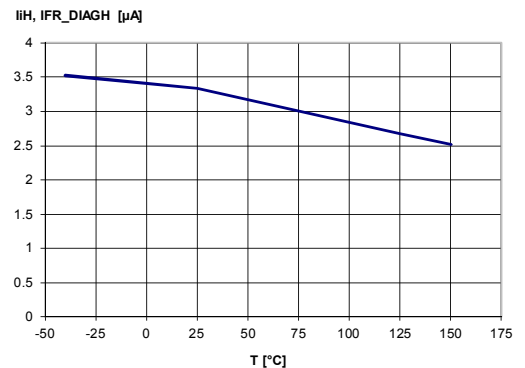
GADG1207161533SMD

Figure 12. Logic input low level voltage



GADG1207161534SMD

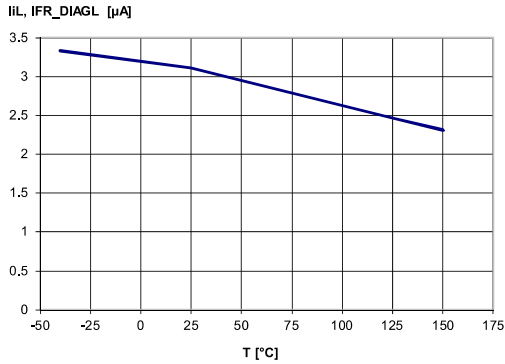
Figure 13. High level logic input current



GADG1207161535SMD

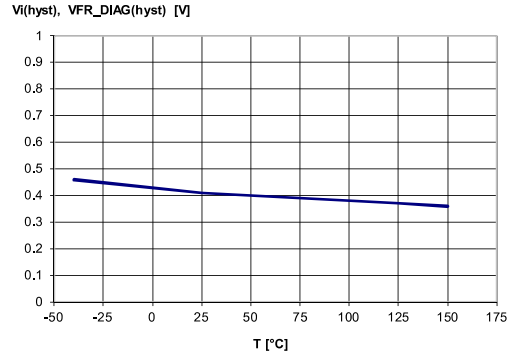


Figure 14. Low level logic input current



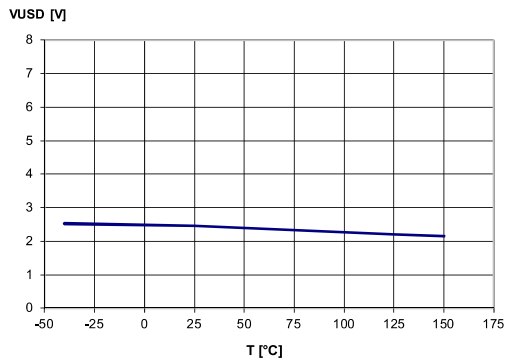
GADG1207161538SMD

Figure 15. Logic input hysteresis voltage



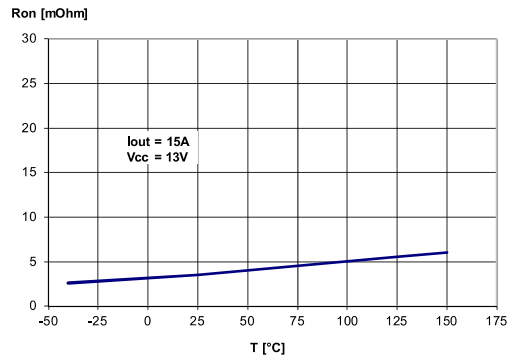
GADG1207161537SMD

Figure 16. Undervoltage shutdown



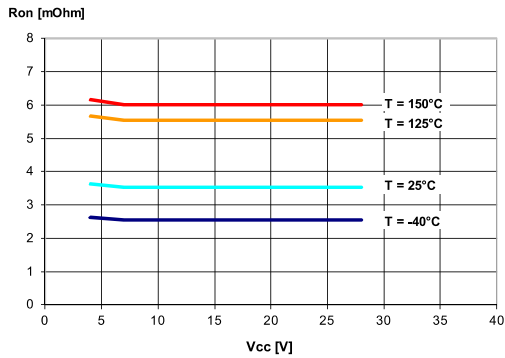
GADG1207161538SMD

Figure 17. On-state resistance vs. T_{case}



GADG1207161539SMD

Figure 18. On-state resistance vs. V_{CC}



GADG1207161540SMD

Figure 19. Turn-on voltage slope

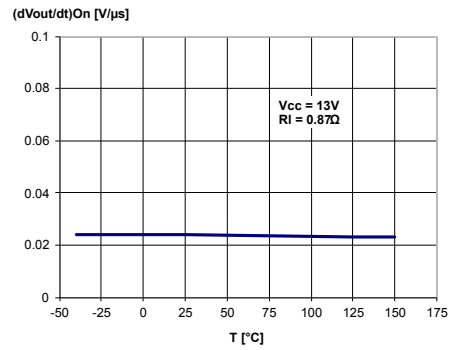




Figure 20. Turn-off voltage slope

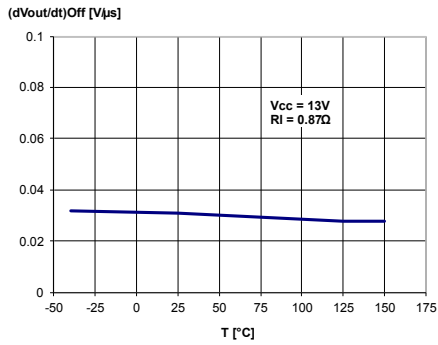


Figure 21. Won vs. T_{case}

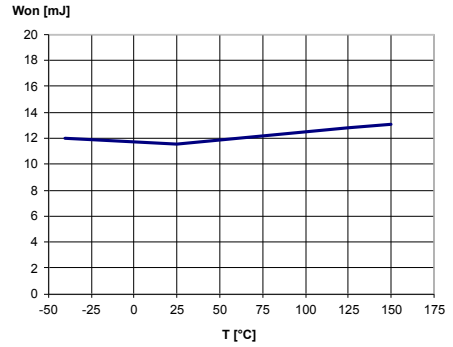


Figure 22. Woff vs. T_{case}

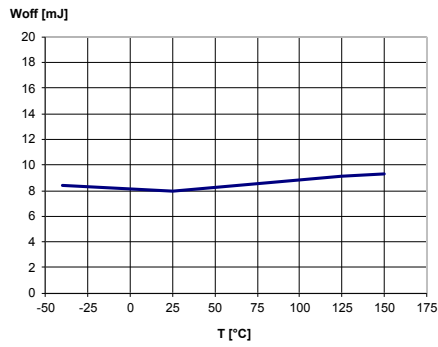
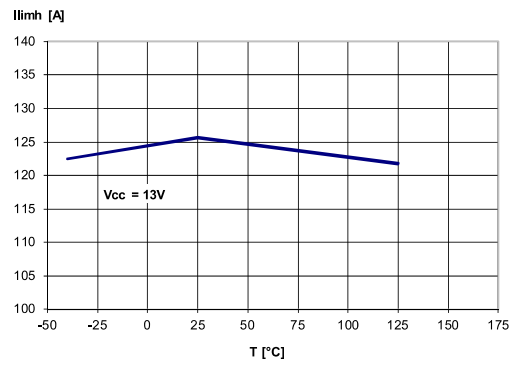
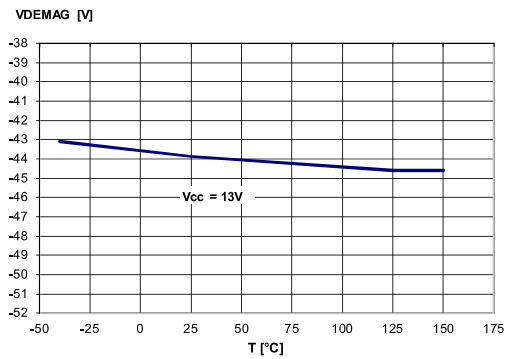


Figure 23. I_{LIMH} vs. T_{case}



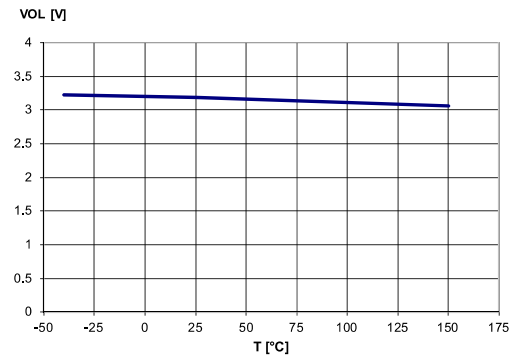
GADG1207161545SMD

Figure 24. Turn-off output voltage clamp

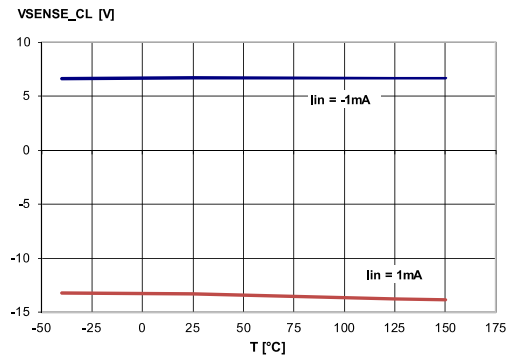


GADG1207161546SMD

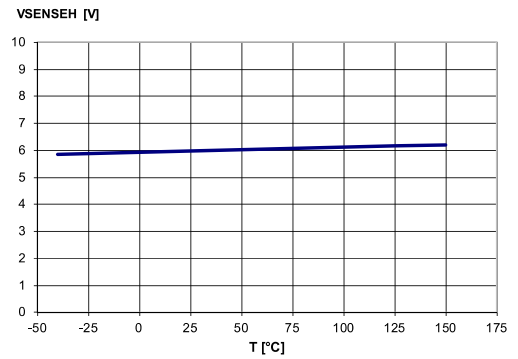
Figure 25. OFF-state open-load voltage detection threshold



GADG1207161547SMD


Figure 26. Vs clamp vs. T_{case}


GADG1207161548SMD

Figure 27. Vsenseh vs. T_{case}


GADG1207161549SMD



3 Protections

3.1 Power limitation

The basic working principle of this protection consists of an indirect measurement of the junction temperature swing ΔT_j through the direct measurement of the spatial temperature gradient on the device surface in order to automatically shut off the output MOSFET as soon as ΔT_j exceeds the safety level of ΔT_{j_SD} . According to the voltage level on the FR_DIAG pin, the output MOSFET switches on and cycles with a thermal hysteresis according to the maximum instantaneous power which can be handled (FR_DIAG = Low) or remains off (FR_DIAG = High). The protection prevents fast thermal transient effects and, consequently, reduces thermo-mechanical fatigue.

3.2 Thermal shutdown

In case the junction temperature of the device exceeds the maximum allowed threshold (typically 175°C), it automatically switches off and the diagnostic indication is triggered. According to the voltage level on the FR_DIAG pin, the device switches on again as soon as its junction temperature drops to T_R (FR_DIAG = Low) or remains off (FR_DIAG = High).

3.3 Current limitation

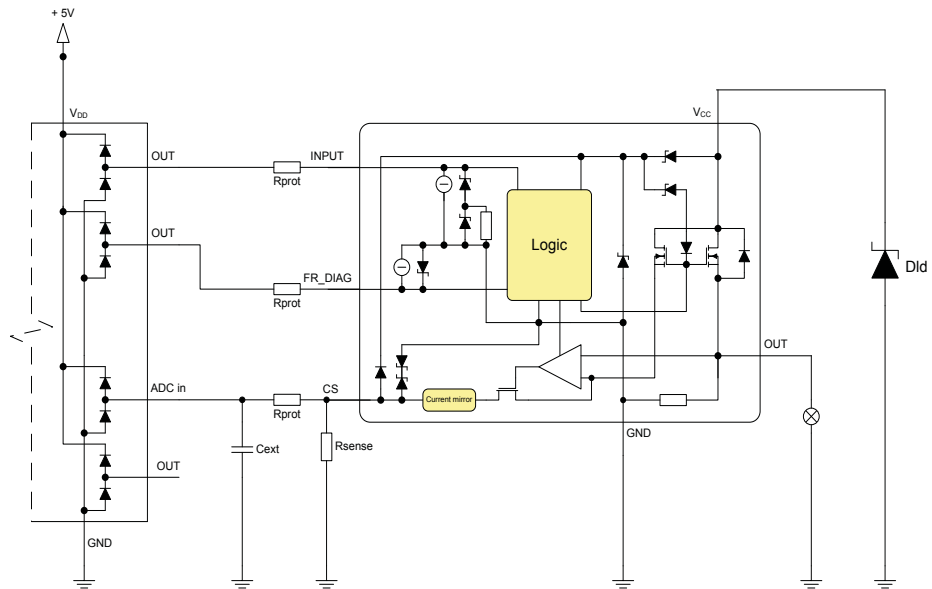
The device is equipped with an output current limiter in order to protect the silicon as well as the other components of the system (e.g. bonding wires, wiring harness, connectors, loads, etc.) from excessive current flow. Consequently, in case of short-circuit, overload or during load power-up, the output current is clamped to a safety level, I_{LIMH} , by operating the output power MOSFET in the active region.

3.4 Negative voltage clamp

In case the device drives inductive load, the output voltage reaches negative values during turn off. A negative voltage clamp structure limits the maximum negative voltage to a certain value, V_{DEMAG} , allowing the inductor energy to be dissipated without damaging the device.

4 Application information

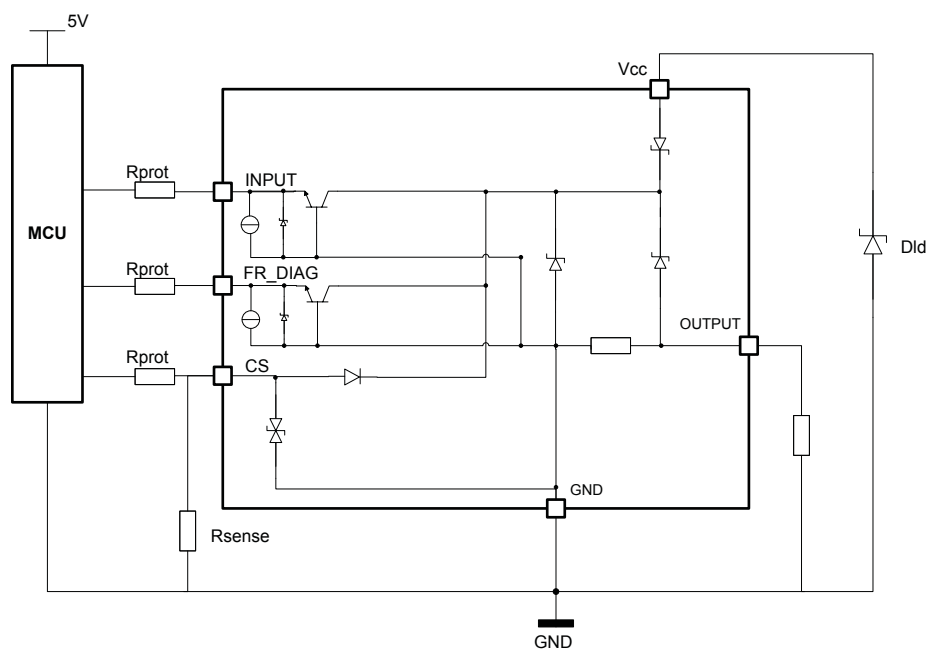
Figure 28. Application diagram



GAPG1607150817CFT

4.1 GND protection network against reverse battery

Figure 29. Simplified internal structure



GAPG1606150821CFT



The device does not need any external components to protect the internal logic in case of a reverse battery condition. The protection is provided by internal structures.

In addition, due to the fact that the output MOSFET turns on even in reverse battery mode, thus providing the same low ohmic path as in regular operating conditions, no additional power dissipation has to be considered.

4.2 Immunity against transient electrical disturbances

The immunity of the device against transient electrical emissions, conducted along the supply lines and injected into the V_{CC} pin, is tested in accordance with ISO7637-2:2011 (E) and ISO 16750-2:2010.

The related function performance status classification is shown in Table 12. ISO 7637-2 - electrical transient conduction along supply line.

Test pulses are applied directly to DUT (Device Under Test) both in ON and OFF-state and in accordance to ISO 7637-2:2011(E), chapter 4. The DUT is intended as the present device only, without components and accessed through V_{CC} and GND terminals.

Status II is defined in ISO 7637-1 Function Performance Status Classification (FPSC) as follows: "The function does not perform as designed during the test but returns automatically to normal operation after the test".

Table 12. ISO 7637-2 - electrical transient conduction along supply line

| Test Pulse 2011(E) | Test pulse severity level with Status II functional performance status | | Minimum number of pulses or test time | Burst cycle / pulse repetition time | | Pulse duration and pulse generator internal impedance |
|---|--|----------------------|---------------------------------------|-------------------------------------|--------|---|
| | Level | U_S ⁽¹⁾ | | min | max | |
| 1 | III | -112V | 500 pulses | 0,5 s | | 2ms, 10 Ω |
| 2a | III | +55V | 500 pulses | 0,2 s | 5 s | 50 μ s, 2 Ω |
| 3a | IV | -220V | 1h | 90 ms | 100 ms | 0.1 μ s, 50 Ω |
| 3b | IV | +150V | 1h | 90 ms | 100 ms | 0.1 μ s, 50 Ω |
| 4 ⁽²⁾ | IV | -7V | 1 pulse | | | 100ms, 0.01 Ω |
| Load dump according to ISO 16750-2:2010 | | | | | | |
| Test B ⁽³⁾ | | 40V | 5 pulse | 1 min | | 400ms, 2 Ω |

1. U_S is the peak amplitude as defined for each test pulse in ISO 7637-2:2011(E), chapter 5.6.

2. Test pulse from ISO 7637-2:2004(E).

3. With 40 V external suppressor referred to ground ($-40^\circ\text{C} < T_j < 150^\circ\text{C}$).

4.3 MCU I/Os protection

If a ground protection network is used and negative transients are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line both to prevent the microcontroller I/O pins from latch-up and to protect the HSD inputs.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

Equation:

$$V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH} \mu C - V_{IH} - V_{GND}) / I_{IHmax}$$

Calculation example:

For $V_{CCpeak} = -150$ V; $I_{latchup} \geq 20$ mA; $V_{OH} \mu C \geq 4.5$ V

$$7.5 \text{ k}\Omega \leq R_{prot} \leq 140 \text{ k}\Omega.$$

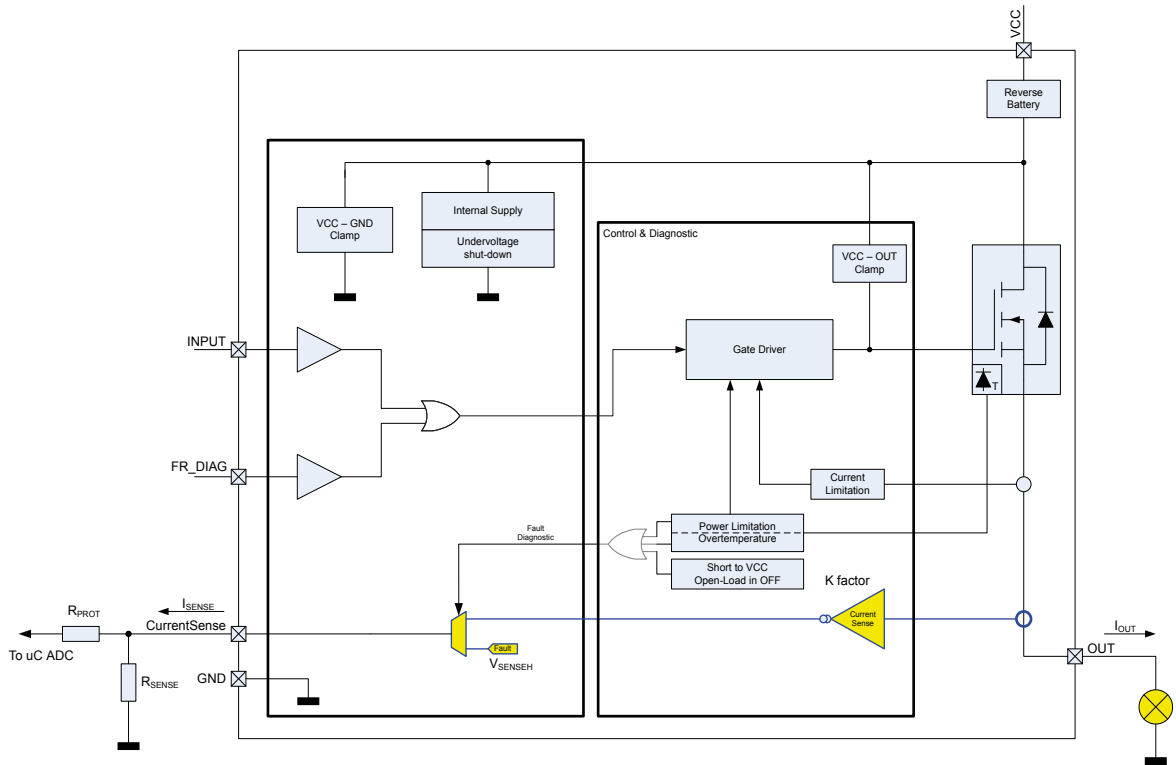
Recommended values: $R_{prot} = 15 \text{ k}\Omega$

4.4 CS - analog current sense

Diagnostic information on device and load status are provided by an analog output pin (CS) delivering the following signal:

- Current monitor: current monitor of channel output current

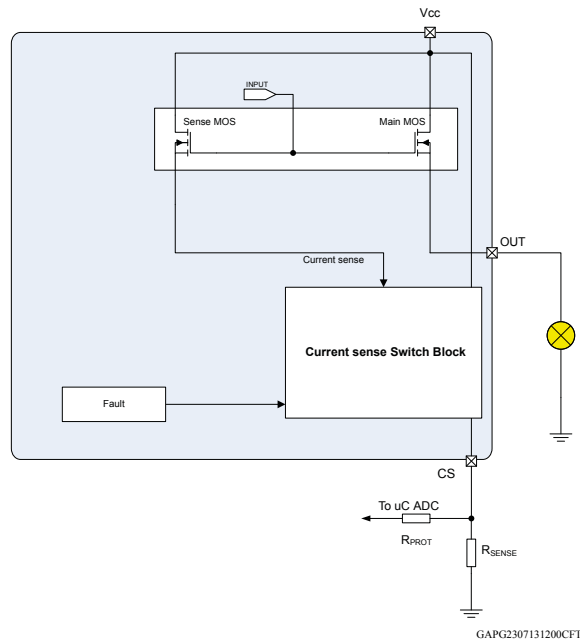
Figure 30. CurrentSense and diagnostic - block diagram



GAPG2704161550CFT

4.4.1 Principle of CurrentSense signal generation

Figure 31. CurrentSense block diagram



Current sense

This output is capable of providing:

- **Current mirror proportional to the load current in normal operation**, delivering current proportional to the load according to a known ratio named **K**
- **Diagnostics flag in fault conditions** delivering fixed voltage V_{SENSEH}

The current delivered by the current sense circuit, I_{SENSE} , can be easily converted to a voltage V_{SENSE} by using an external sense resistor, R_{SENSE} , allowing continuous load monitoring and abnormal condition detection.

Normal operation (channel ON, no fault)

While the device is operating in normal conditions (no fault intervention), V_{SENSE} calculation can be done using simple equations

Current provided by CurrentSense output: $I_{SENSE} = I_{OUT}/K$

Voltage on R_{SENSE} : $V_{SENSE} = R_{SENSE} \cdot I_{SENSE} = R_{SENSE} \cdot I_{OUT}/K$

Where :

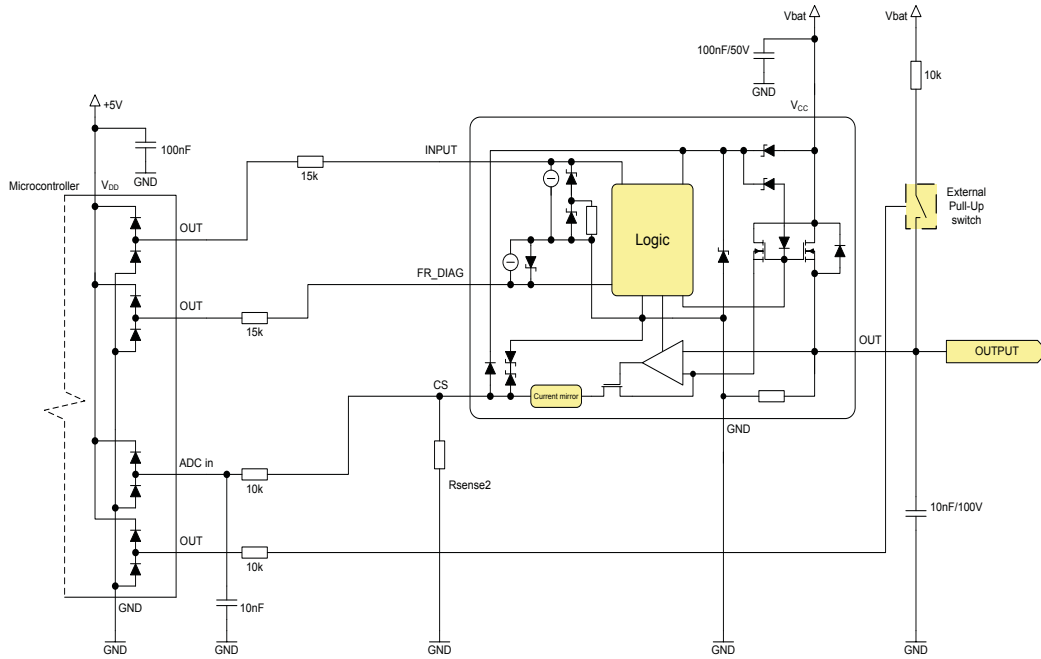
- V_{SENSE} is the voltage measurable on R_{SENSE} resistor
- I_{SENSE} is the current provided from the CS pin in current output mode
- I_{OUT} is the current flowing through output
- K factor represents the ratio between PowerMOS cells and SenseMOS cells; its spread includes geometric factor spread, current sense amplifier offset and process parameters spread of the overall circuitry specifying the ratio between I_{OUT} and I_{SENSE} .

Failure flag indication

In case of power limitation/overtemperature, the fault is indicated by the CS pin which is switched to a "current limited" voltage source, V_{SENSEH} .

In any case, the current sourced by the CS in this condition is limited to I_{SENSEH} .

Figure 32. Analogue HSD – open-load detection in off-state



GAPG1606150857CFT

Figure 33. Open-load / short to V_{CC} condition

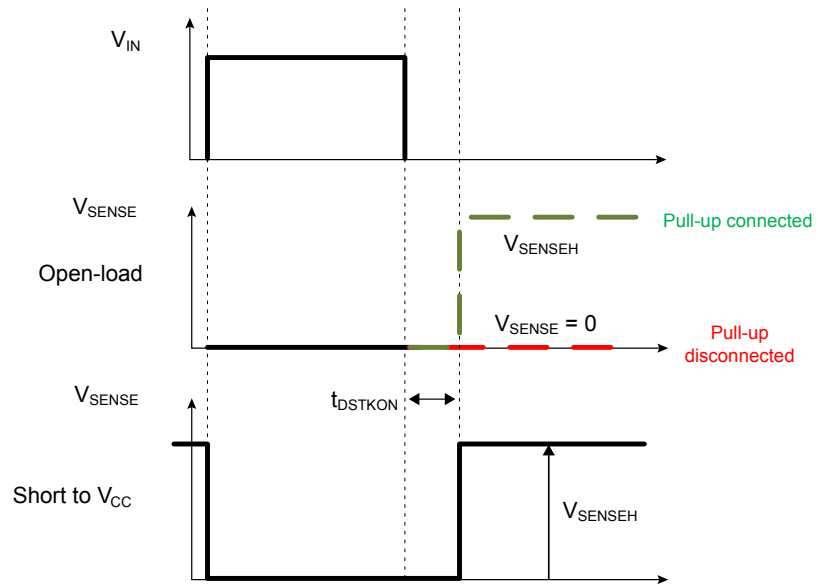



Table 13. CurrentSense pin levels in off-state

| Condition | Output | CurrentSense | FR_DIAG |
|-------------------|--------------------|--------------|---------|
| Open-load | $V_{OUT} > V_{OL}$ | Hi-Z | L |
| | | V_{SENSEH} | H |
| | $V_{OUT} < V_{OL}$ | Hi-Z | L |
| | | 0 | H |
| Short to V_{CC} | $V_{OUT} > V_{OL}$ | Hi-Z | L |
| | | V_{SENSEH} | H |
| Nominal | $V_{OUT} < V_{OL}$ | Hi-Z | L |
| | | 0 | H |

4.4.2 Short to VCC and OFF-state open-load detection

Short to V_{CC}

A short circuit between V_{CC} and output is indicated by the relevant current sense pin set to V_{SENSEH} during the device off-state. Small or no current is delivered by the current sense during the on-state depending on the nature of the short circuit.

OFF-state open-load with external circuitry

Detection of an open-load in off mode requires an external pull-up resistor R_{PU} connecting the output to a positive supply voltage V_{PU} .

It is preferable V_{PU} to be switched off during the module standby mode in order to avoid the overall standby current consumption to increase in normal conditions, i.e. when load is connected.

R_{PU} must be selected in order to ensure $V_{OUT} > V_{OLmax}$ in accordance with the following equation:

$$R_{PU} < \frac{V_{PU} - 4}{I_{L(off2)min @ 4V}}$$

5 Package and PCB thermal data

5.1 Octapak thermal data

Figure 34. Octapak on two-layer PCB (2s0p to JEDEC JESD 51-5)

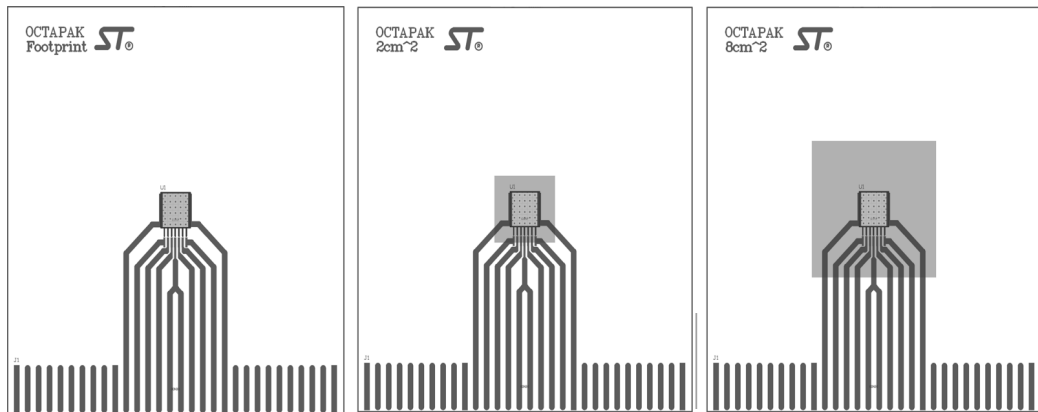


Figure 35. Octapak on four-layer PCB (2s2p to JEDEC JESD 51-7)

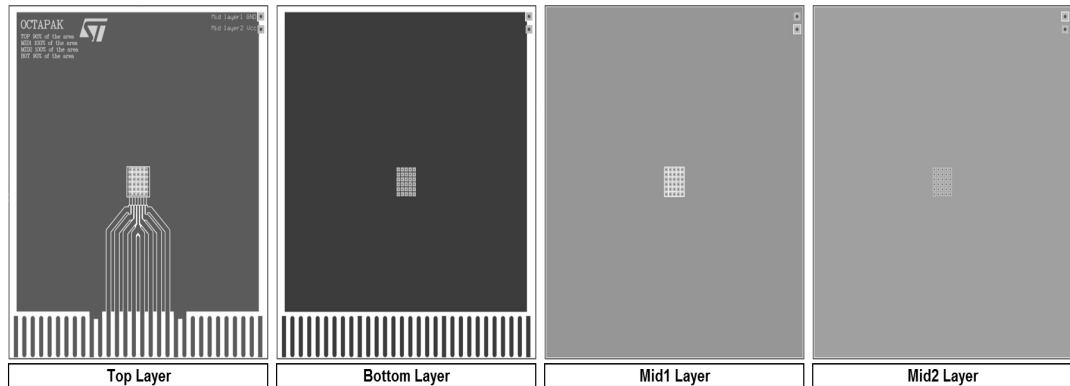


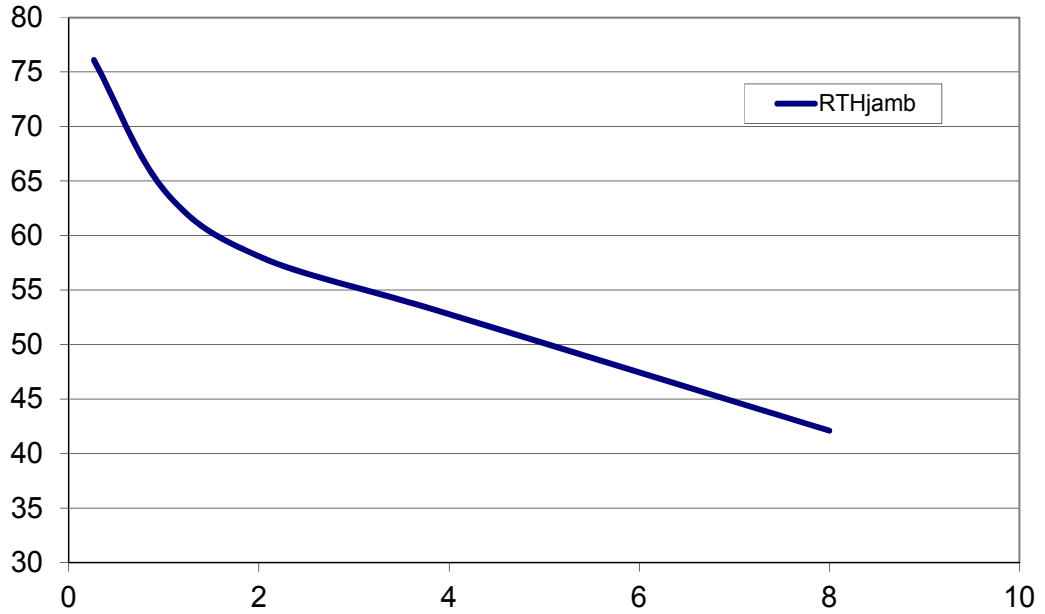
Table 14. PCB properties

| Dimension | Value |
|--|--------------------|
| Board finish thickness | 1.6 mm +/- 10% |
| Board dimension | 77 mm x 86 mm |
| Board Material | FR4 |
| Copper thickness (top and bottom layers) | 0.070 mm |
| Copper thickness (inner layers) | 0.035 mm |
| Thermal vias separation | 1.2 mm |
| Thermal via diameter | 0.3 mm +/- 0.08 mm |
| Copper thickness on vias | 0.025 mm |
| Footprint dimension (top layer) | 6.4 mm x 7 mm |



| Dimension | Value |
|---|---|
| Heatsink copper area dimension (bottom layer) | Footprint, 2 cm ² or 8 cm ² |

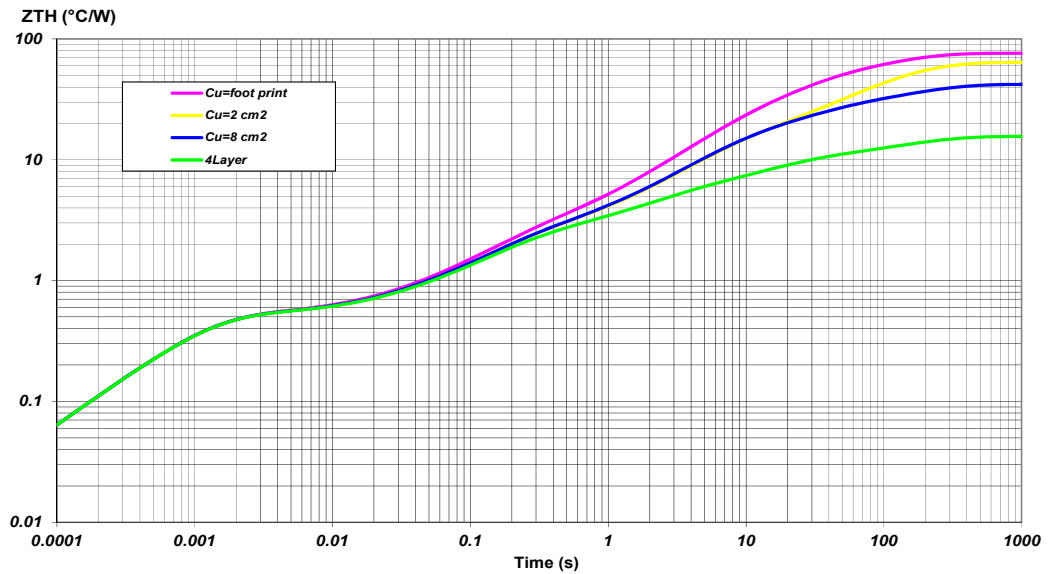
Figure 36. R_{thj-amb} vs PCB copper area in open box free air conditions



RTHj_amb on 4Layer PCB: 15.6°C/W

GADG1107161840SMD

Figure 37. Octapak thermal impedance junction ambient single pulse

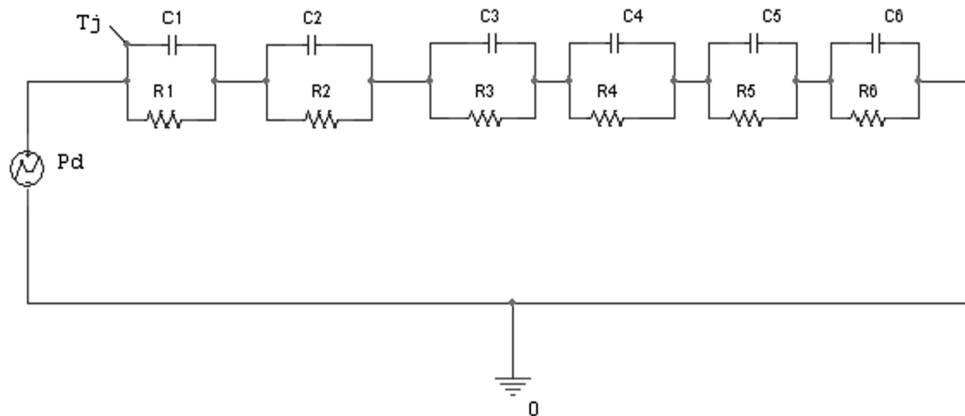


GADG1107161845SMD

Pulse calculation formula

Equation:

$$Z_{TH\delta} = R_{TH} \cdot + Z_{THtp} (1 - \delta)$$

 where $\delta = t_p/T$
Figure 38. Thermal fitting model for Octapak


Note: The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protections (power limitation or thermal cycling during thermal shutdown) are not triggered.

Table 15. Thermal parameters

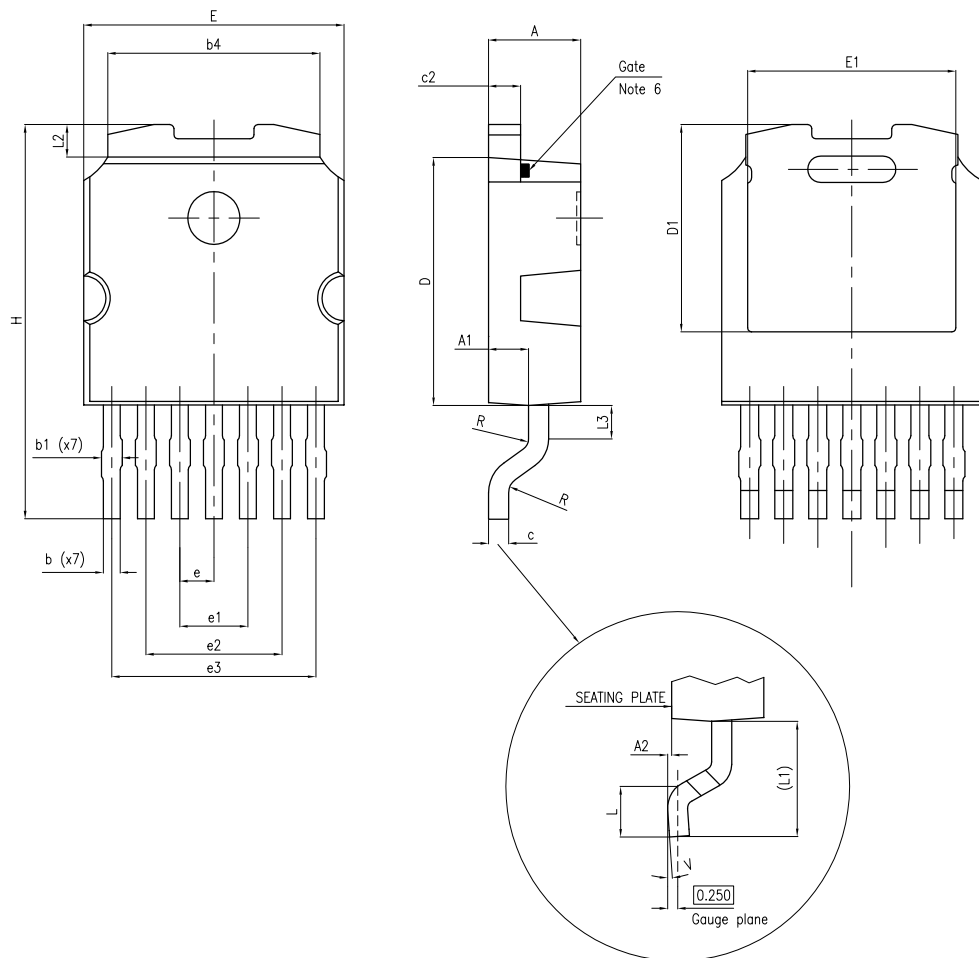
| Area/island (cm ²) | Footprint | 2 | 8 | 4L |
|--------------------------------|-----------|--------|--------|--------|
| R1 (°C/W) | 0.01 | 0.01 | 0.01 | 0.01 |
| R2 (°C/W) | 0.5 | 0.5 | 0.5 | 0.5 |
| R3 (°C/W) | 1.6 | 1.6 | 1.6 | 1.6 |
| R4 (°C/W) | 10 | 10 | 10 | 2.5 |
| R5 (°C/W) | 28 | 20 | 12 | 5 |
| R6 (°C/W) | 36 | 26 | 18 | 6 |
| C1 (W.s/°C) | 0.001 | 0.001 | 0.001 | 0.001 |
| C2 (W.s/°C) | 0.0018 | 0.0018 | 0.0018 | 0.0018 |
| C3 (W.s/°C) | 0.11 | 0.11 | 0.11 | 0.11 |
| C4 (W.s/°C) | 0.6 | 0.6 | 0.6 | 0.8 |
| C5 (W.s/°C) | 0.8 | 1.4 | 2.2 | 3 |
| C6 (W.s/°C) | 3 | 6 | 9 | 25 |

6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

6.1 Octapak package information

Figure 39. Octapak package dimensions



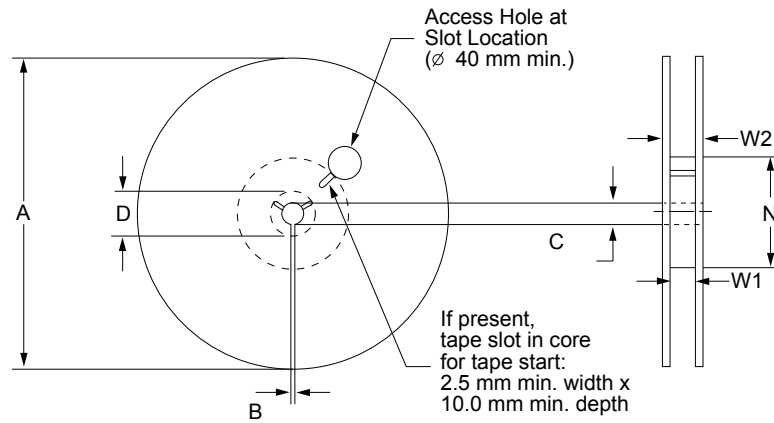
GAPGCFI00665


Table 16. Octapak mechanical data

| Symbol | Millimeters | | |
|--------|-------------|------|-------|
| | Min. | Typ. | Max. |
| A | 2.20 | 2.30 | 2.40 |
| A1 | 0.90 | 1.00 | 1.10 |
| A2 | 0.03 | | 0.15 |
| b | 0.38 | 0.45 | 0.52 |
| b1 | | | 0.70 |
| b4 | 5.20 | 5.30 | 5.40 |
| c | 0.45 | 0.50 | 0.60 |
| c2 | 0.75 | 0.80 | 0.90 |
| D | 6.00 | 6.10 | 6.20 |
| D1 | | 5.15 | |
| E | 6.40 | 6.50 | 6.60 |
| E1 | | 5.30 | |
| e | 0.85 BSC | | |
| e1 | 1.60 | 1.70 | 1.80 |
| e2 | 3.30 | 3.40 | 3.50 |
| e3 | 5.00 | 5.10 | 5.20 |
| H | 9.35 | 9.70 | 10.10 |
| L | 1.00 | | — |
| (L1) | | 2.80 | |
| L2 | | 0.80 | |
| L3 | | 0.85 | |
| R | 0.40 BSC | | |
| V2 | 0° | | 8° |

6.2 Octapak packing information

Figure 40. Octapak reel 13"



TAPG2004151655CFT

Table 17. Reel dimensions

| Description | Value ⁽¹⁾ |
|----------------|----------------------|
| Base quantity | 2500 |
| Bulk quantity | 2500 |
| A (max) | 330 |
| B (min) | 1.5 |
| C (+0.5, -0.2) | 13 |
| D | 20.2 |
| N | 100 |
| W1 (+2 /-0) | 16.4 |
| W2 (max) | 22.4 |

1. All dimensions are in mm.



Figure 41. Octapak carrier tape

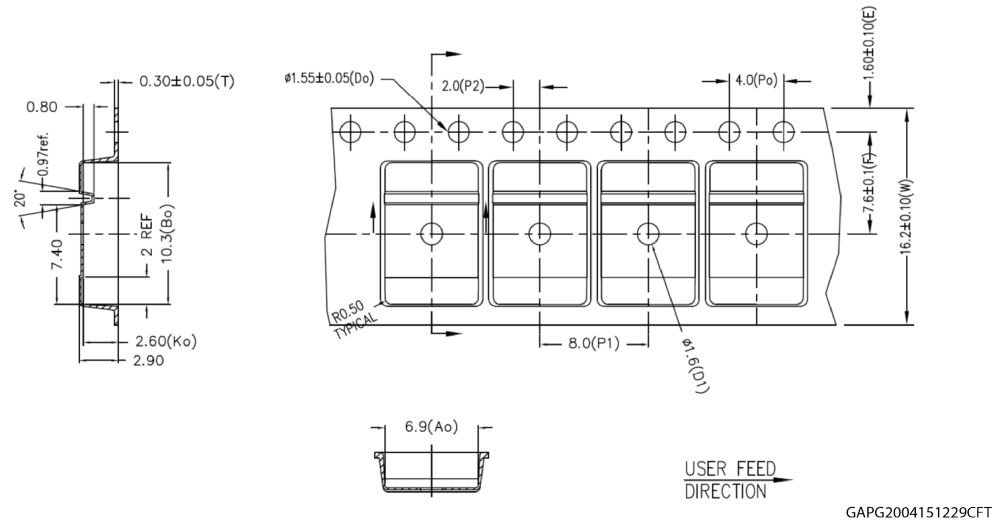
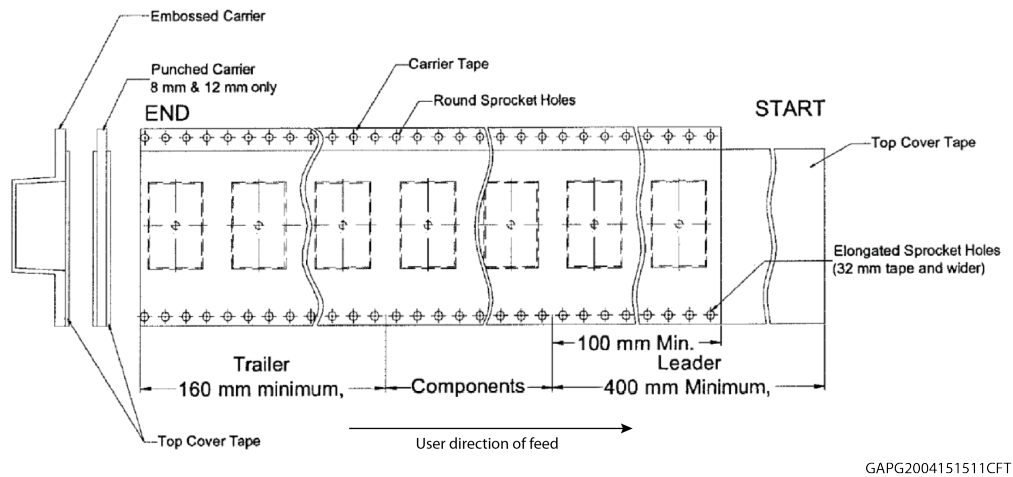
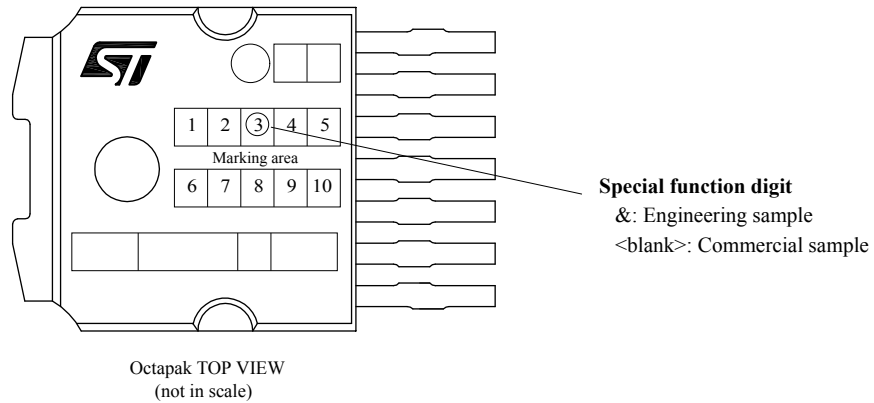


Figure 42. Octapak schematic drawing of leader and trailer tape



6.3 Octapak marking information

Figure 43. Octapak marking information



GAPG1604151015CFT

Parts marked as "&" are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.



Revision history

Table 18. Document revision history

| Date | Version | Changes |
|-------------|---------|--|
| 15-Mar-2021 | 1 | Initial release. |
| 28-Oct-2021 | 2 | Updated features in cover page. Updated Table 5. Power section and Table 9. CurrentSense . Added Section 2.4 Electrical characteristics curves . |



Contents

| | | |
|----------|--|-----------|
| 1 | Block diagram and pin description | 2 |
| 2 | Electrical specification | 4 |
| 2.1 | Absolute maximum ratings | 4 |
| 2.2 | Thermal data | 5 |
| 2.3 | Main electrical characteristics | 5 |
| 2.4 | Electrical characteristics curves | 12 |
| 3 | Protections | 16 |
| 3.1 | Power limitation | 16 |
| 3.2 | Thermal shutdown | 16 |
| 3.3 | Current limitation | 16 |
| 3.4 | Negative voltage clamp | 16 |
| 4 | Application information | 17 |
| 4.1 | GND protection network against reverse battery | 17 |
| 4.2 | Immunity against transient electrical disturbances | 18 |
| 4.3 | MCU I/Os protection | 18 |
| 4.4 | CS - analog current sense | 19 |
| 4.4.1 | Principle of CurrentSense signal generation | 20 |
| 4.4.2 | Short to VCC and OFF-state open-load detection | 22 |
| 5 | Package and PCB thermal data | 23 |
| 5.1 | Octapak thermal data | 23 |
| 6 | Package information | 26 |
| 6.1 | Octapak package information | 26 |
| 6.2 | Octapak packing information | 28 |
| 6.3 | Octapak marking information | 30 |
| | Revision history | 31 |



List of tables

| | | |
|------------------|--|----|
| Table 1. | Pin functions | 2 |
| Table 2. | Suggested connections for unused and not connected pins | 3 |
| Table 3. | Absolute maximum ratings | 4 |
| Table 4. | Thermal data | 5 |
| Table 5. | Power section | 5 |
| Table 6. | Switching | 6 |
| Table 7. | Logic inputs | 6 |
| Table 8. | Protections | 7 |
| Table 9. | CurrentSense | 7 |
| Table 10. | Truth table | 11 |
| Table 11. | FR_DIAG functionality | 11 |
| Table 12. | ISO 7637-2 - electrical transient conduction along supply line | 18 |
| Table 13. | CurrentSense pin levels in off-state | 22 |
| Table 14. | PCB properties | 23 |
| Table 15. | Thermal parameters | 25 |
| Table 16. | Octapak mechanical data | 27 |
| Table 17. | Reel dimensions | 28 |
| Table 18. | Document revision history | 31 |



List of figures

| | | |
|------------|--|----|
| Figure 1. | Block diagram | 2 |
| Figure 2. | Configuration diagram (top view) | 3 |
| Figure 3. | Current and voltage conventions | 4 |
| Figure 4. | I_{OUT}/I_{SENSE} versus I_{OUT} | 9 |
| Figure 5. | Current sense precision vs. I_{OUT} | 10 |
| Figure 6. | Switching times and Pulse skew | 10 |
| Figure 7. | T_{DSTKON} | 11 |
| Figure 8. | OFF-state output current | 12 |
| Figure 9. | Standby current | 12 |
| Figure 10. | $I_{GND(ON)}$ vs. I_{out} | 12 |
| Figure 11. | Logic input high level voltage | 12 |
| Figure 12. | Logic input low level voltage | 12 |
| Figure 13. | High level logic input current | 12 |
| Figure 14. | Low level logic input current | 13 |
| Figure 15. | Logic input hysteresis voltage | 13 |
| Figure 16. | Undervoltage shutdown | 13 |
| Figure 17. | On-state resistance vs. T_{case} | 13 |
| Figure 18. | On-state resistance vs. V_{CC} | 13 |
| Figure 19. | Turn-on voltage slope | 13 |
| Figure 20. | Turn-off voltage slope | 14 |
| Figure 21. | W_{on} vs. T_{case} | 14 |
| Figure 22. | W_{off} vs. T_{case} | 14 |
| Figure 23. | I_{LIMH} vs. T_{case} | 14 |
| Figure 24. | Turn-off output voltage clamp | 14 |
| Figure 25. | OFF-state open-load voltage detection threshold | 14 |
| Figure 26. | V_s clamp vs. T_{case} | 15 |
| Figure 27. | V_{senseh} vs. T_{case} | 15 |
| Figure 28. | Application diagram | 17 |
| Figure 29. | Simplified internal structure | 17 |
| Figure 30. | CurrentSense and diagnostic - block diagram | 19 |
| Figure 31. | CurrentSense block diagram | 20 |
| Figure 32. | Analogue HSD – open-load detection in off-state | 21 |
| Figure 33. | Open-load / short to V_{CC} condition | 21 |
| Figure 34. | Octapak on two-layer PCB (2s0p to JEDEC JESD 51-5) | 23 |
| Figure 35. | Octapak on four-layer PCB (2s2p to JEDEC JESD 51-7) | 23 |
| Figure 36. | $R_{thj-amb}$ vs PCB copper area in open box free air conditions | 24 |
| Figure 37. | Octapak thermal impedance junction ambient single pulse | 24 |
| Figure 38. | Thermal fitting model for Octapak | 25 |
| Figure 39. | Octapak package dimensions | 26 |
| Figure 40. | Octapak reel 13" | 28 |
| Figure 41. | Octapak carrier tape | 29 |
| Figure 42. | Octapak schematic drawing of leader and trailer tape | 29 |
| Figure 43. | Octapak marking information | 30 |

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, please refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2021 STMicroelectronics – All rights reserved

OUR CERTIFICATE

DiGi provide top-quality products and perfect service for customer worldwide through standardization, technological innovation and continuous improvement. DiGi through third-party certification, we stricly control the quality of products and services. Welcome your RFQ to

Email: Info@DiGi-Electronics.com



Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com

DiGi is a global authorized distributor of electronic components.